## Applicant(s)/Patent Under Application/Control No. Reexamination 10/625,824 CHANG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2123 · Eunhee Kim **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 701/211 US-2002/0010543 01-2002 Watanabe et al. Α US-В US-С US-D US-Ε US-F US-G US-Н US-1 US-US-K US-US-M FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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